Sheet I of I Form PTO-1449 U.S. DEPARTMENT OF COMMERCE ATTY, DOCKET NO. SERIAL NO. 09 332,271 PATENT AND TRADEMARK OFFICE CITE BY APPLICANT APPLICANT if necessary) Klaus Florian Schuegraf FILING DATE GROUP 2812 U.S. PATENT DOCUMENTS *Examine: Document Name Class Subclass Initial Filing Date Number If Appropriate 5.472.896 12 95 Chen et al. 437 11 ΑB 5,393.685 02 95 Yoo et al. 11 AC 4,833.099 05 89 Woo 43-41 AD 5.915.197 06 99 Yamanaka et al. 438 536 ΑE ΑF AG AΗ Al ΑJ ΑK AL FOREIGN PATENT DOCUMENTS Document Date Country Class Subclass Translation Number Yes AMAN AO AQ OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AR A\$ ΑT EXAMINER DATE CONSIDERED *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 669: Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Form PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY, DOCKET NO. MI22-532

SERIAL NO. 09/332.271

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RP	AA	4,354,309	10/1982	Gardiner et al.					
RP	AB	4,559,091	12/1985	Allen et al.		148	174		
<u> </u>	ΑC	4.386.765	12/1989	Chen et al.		437	200		
KP.	AD	5,192,708	03/1993	Beyer et al.		437	90		
KP.	AE	5,393,676	02/1995	Anjum et al.		437	24		
KY	AF	5,712,181	01/1998	Byun et al.		437	46		
RP	AG	5,798,296	08/1998	Fazan et al.		438	592		
RP	AH	5,811,343	09/1998	Wann et al.	···	438	305		
RP	AI	5,985,720	11/1999	Saitob		438	266		
K)	AJ	6,040,238	03/2000	Yang et al.		438	592		
KV.	AK _.	5,164,333	11/1992	Schwalke et al.		437	200		
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RP	м	5,350,698	09/1994	Huang et al.		437	26		
RP	AB	5,441,904	08/1995	Kim et al.		437	40		
<u>KI</u>	AC	5,481,128	01/1996	Hong		257	320		
R	AD	6,060,741	05/2000	Huang		257	315		
RI	λE	6,208,004 B1	03/2001	Cuningham		257	413	ļ	
H	AF	6,239,458 B1	05/2001	Liaw et al.	·	257	296		
41)	AG	5,767,004	06,93	Balasubramanian et al.					
RU	AH	5,840,607	11/98	Yeh et al.		<u> </u>	ļ		
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ATTY, DOCKET NO. MI22-532

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RP	АВ	5.818.092	10, 1998	Bai et al.		257	388			
	AC	6.262,458 B1	07/2001	Hu		257	334			
KP	AD	5.986.312	11/1999	Kuroda		257	382		•	
R	AE	5,723,893	03/1998	Yu et al.		257	413			
RP	AF	5,710,454	01/1998	Wu .		257	413			
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7		Society, March 1966.	Society, March 1966; pp. 263-269										
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